FRANKEN ET AL. - 10/615,421 Client/Matter: 081468-0304791

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

- (Currently amended) A lithographic projection apparatus, comprising: 1.
 - a radiation system constructed and arranged to provide a projection beam of radiation;
- a support structure constructed and arranged to support a patterning device, the patterning device constructed and arranged to pattern the projection beam according to a desired pattern:
 - a substrate table constructed and arranged to hold a substrate;
- a projection system constructed and arranged to project the patterned beam onto a target portion of the substrate;
 - a base to which the support structure and the substrate table are mounted; and
- a reference frame compliantly mounted to the base, wherein the projection system comprises at least one optical element mounted on a projection frame that is compliantly mounted to the reference frame.
- 2. (Original) A lithographic projection apparatus according to claim 1, wherein an eigenfrequency of the projection frame compliantly mounted to the reference frame is between about 10 and 30 Hz.
- (Original) A lithographic projection apparatus according to claim 1, wherein an eigenfrequency of the reference frame compliantly mounted to the base is about 0.5 Hz.
- 4. (Original) A lithographic projection apparatus according to claim 1, wherein the projection system is compliantly mounted to the reference frame by at least three compliant mounts.
- 5. (Original) A lithographic projection apparatus according to claim 1, wherein the projection system is mounted to the reference frame on nodal axes of a dominant mode of bending vibration of the reference frame or a torsional vibration of the reference frame.

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- 6. (Original) A lithographic projection apparatus according to claim 1, wherein the projection system is compliantly mounted to the reference frame by at least one compliant mount, the compliant mount comprising:
- a T-shaped member with one of the projection system and the reference frame attached to both ends of a first elongate member of the T-shaped member and the other of the projection system and the reference frame is attached to an end of a second elongate member of the T-shaped member.
- 7. (Original) A lithographic projection apparatus according to claim 6, wherein the T-shaped member has an internal first eigenfrequency that is greater than 1000 Hz.
- 8. (Original) A lithographic projection apparatus according to claim 1, wherein the projection system is compliantly mounted to the reference frame by at least one compliant mount that is one of an air-mount, a spring and a magnetic support.
- 9. (Original) A lithographic projection apparatus according to claim 1, wherein motion of the projection system relative to the reference frame is damped.
- 10. (Original) A lithographic projection apparatus according to claim 9, wherein the motion of the projection system relative to the reference frame is actively damped by piezoelectric actuators or Lorentz-force actuators.
- 11. (Currently amended) A device manufacturing method, comprising:

 providing a substrate that is at least partially covered by a layer of radiation sensitive material:

projecting a patterned beam of radiation onto a target portion of [[the]] a layer of radiation-sensitive material at least partially covering a substrate using a projection system;

supporting a reference frame, a support structure constructed and arranged to support a patterning device, and a substrate table constructed and arranged to hold the substrate, on a base, wherein the reference frame is compliantly mounted to the base and the projection system is mounted to the reference frame; and

compliantly mounting the projection system to the reference frame while projecting the patterned beam of radiation onto the target portion.

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- 12. (Original) A method according to claim 11, wherein the projection system comprises at least one optical element mounted on a projection frame that is compliantly mounted to the reference frame and an eigenfrequency of the projection frame compliantly mounted to the reference frame is between about 10 and 30 Hz.
- 13. (Original) A method according to claim 11, wherein an eigenfrequency of the reference frame compliantly mounted to the base is about 0.5 Hz.
- 14. (Original) A method according to claim 11, wherein the projection system is compliantly mounted to the reference frame by at least three compliant mounts.
- 15. (Original) A method according to claim 11, wherein the projection system is compliantly mounted to the reference frame on nodal axes of a dominant mode of bending vibration of the reference frame or a torsional vibration of the reference frame.
- 16. (Original) A method according to claim 11, wherein the projection system is compliantly mounted to the reference frame by at least one compliant mount, the compliant mount comprising:
- a T-shaped member with one of the projection system and the reference frame attached to both ends of a first elongate member of the T-shaped member and the other of the projection system and the reference frame attached to an end of a second elongate member of the T-shaped member.
- 17. (Original) A method according to claim 16, wherein the T-shaped member has an internal first eigenfrequency that is greater than 1000 Hz.
- 18. (Original) A method according to claim 11, wherein the projection system is compliantly mounted to the reference frame by at least one compliant mount that is one of an air-mount, a spring and a magnetic support.
- 19. (Original) A method according to claim 11, wherein motion of the projection system relative to the reference frame is damped.

- 20. (Original) A method according to claim 19, wherein the motion of the projection system relative to the reference frame is actively damped by piezoelectric actuators or Lorentz-force actuators.
- 21. (Currently amended) A lithographic projection apparatus, comprising:
 - a radiation system constructed and arranged to provide a projection beam of radiation;
- a support structure constructed and arranged to support a patterning device, the patterning device constructed and arranged to pattern the projection beam according to a desired pattern;
 - a substrate table constructed and arranged to hold a substrate;
- a projection system constructed and arranged to project the patterned beam onto a target portion of the substrate;
 - a base to which the support structure and the substrate table are mounted;
- a reference frame mounted to the base, wherein the projection system comprises at least one optical element mounted on a projection frame that is mounted to the reference frame:
- at least one first isolation mount operatively between the reference frame and the base to inhibit vibrations or movements of a predetermined type from being transmitted from the base to the reference frame; and
- at least one second isolation mount operatively between the reference frame and the projection frame to inhibit vibrations or movements of a predetermined type from being transmitted from the reference frame to the projection frame.